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LM5109A High Voltage 1A Peak Half Bridge Gate Driver



LM5109A High Voltage 1A Peak Half Bridge Gate Driver **General Description**

The LM5109A is a cost effective, high voltage gate driver designed to drive both the high-side and the low-side N-Channel MOSFETs in a synchronous buck or a half bridge configuration. The floating high-side driver is capable of working with rail voltages up to 90V. The outputs are independently controlled with TTL compatible input thresholds. The robust level shift technology operates at high speed while consuming low power and providing clean level transitions from the control input logic to the high-side gate driver. Under-voltage lockout is provided on both the lowside and the high-side power rails. The device is available in the SOIC-8 and the thermally enhanced LLP-8 packages.

Features

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- Drives both a high-side and low-side N-Channel MOSFET
- 1A peak output current (1.0A sink / 1.0A source)
- Independent TTL compatible inputs

- Bootstrap supply voltage to 108V DC
- Fast propagation times (30 ns typical)
- Drives 1000 pF load with 15ns rise and fall times
- Excellent propagation delay matching (2 ns typical)
- Supply rail under-voltage lockout
- Low power consumption
- Pin compatible with ISL6700

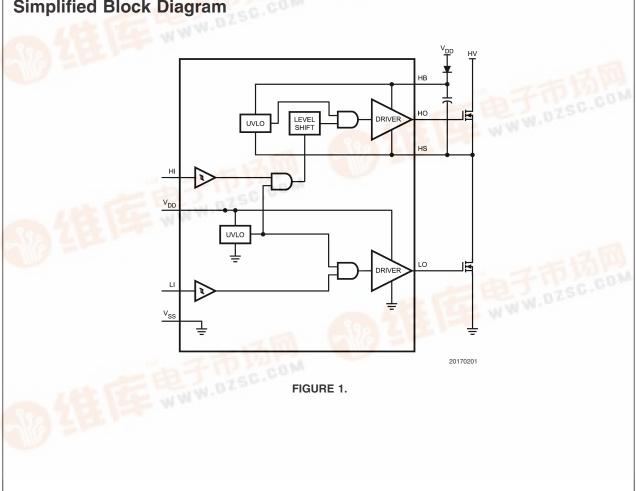
Typical Applications

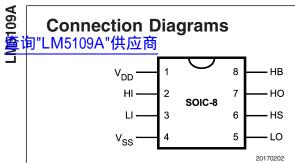
- Current Fed push-pull converters
- Half and Full Bridge power converters
- Solid state motor drives
- Two switch forward power converters

Package

- SOIC-8
- LLP-8 (4 mm x 4 mm)







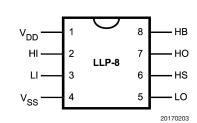


FIGURE 2.

Ordering Information

| Ordering Number | Package Type | NSC Package Drawing | Supplied As |
|-----------------|--------------|---------------------|-------------------------------|
| LM5109AMA | SOIC-8 | M08A | 95 Units in anti static rails |
| LM5109AMAX | SOIC-8 | M08A | 2500 Units on Tape & Reel |
| LM5109ASD | LLP-8 | SDC08A | 1000 Units on Tape & Reel |
| LM5109ASDX | LLP-8 | SDC08A | 4500 Units on Tape & Reel |

Pin Descriptions

| Pin # | | Nama | Description | Anniliantian Information | | |
|-------|-------|-----------------|--|--|--|--|
| SO-8 | LLP-8 | Name | Description | Application Information | | |
| 1 | 1 | V _{DD} | Positive gate drive supply | Locally decouple to V_{SS} using low ESR/ESL capacitor located as close to IC as possible. | | |
| 2 | 2 | н | High side control input | The HI input is compatible with TTL input thresholds. Unused HI input should be tied to ground and not left open | | |
| 3 | 3 | LI | Low side control input | The LI input is compatible with TTL input thresholds. Unused LI input should be tied to ground and not left open. | | |
| 4 | 4 | V _{SS} | Ground reference | All signals are referenced to this ground. | | |
| 5 | 5 | LO | Low side gate driver output | Connect to the gate of the low-side N-MOS device. | | |
| 6 | 6 | HS | High side source connection | Connect to the negative terminal of the bootstrap capacitor and to the source of the high-side N-MOS device. | | |
| 7 | 7 | HO | High side gate driver output | Connect to the gate of the high-side N-MOS device. | | |
| 8 | 8 | HB | High side gate driver positive supply rail | Connect the positive terminal of the bootstrap capacitor to HB and the negative terminal of the bootstrap capacitor to HS. The bootstrap capacitor should be placed as close to IC as possible. | | |

Note: For LLP-8 package it is recommended that the exposed pad on the bottom of the package be soldered to ground plane on the PCB and the ground plane should extend out from underneath the package to improve heat dissipation.

Storage Temperature Range ESD Rating HBM (Note 2) –55°C to +150°C 1.5 kV LM5109A

| V _{DD} |
|----------------------|
| HS (Note 6) |
| HB |
| HS Slew Rate |
| Junction Temperature |

8V to 14V -1V to 90V V_{HS} +8V to V_{HS} +14V < 50 V/ns -40°C to +125°C

Electrical Characteristics

 V_{DD} to V_{SS}

LI or HI to V_{SS}

HS to V_{SS} (Note 6)

Junction Temperature

HB to HS

LO to V_{SS}

HO to V_{SS}

HB to $V_{\mbox{\scriptsize SS}}$

Specifications in standard typeface are for $T_J = +25$ °C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, $V_{DD} = V_{HB} = 12V$, $V_{SS} = V_{HS} = 0V$, No Load on LO or HO (Note 4).

-0.3V to 18V

-0.3V to 18V

-5V to 90V

-40°C to +150°C

108V

-0.3V to V_{DD} +0.3V

-0.3V to V_{DD} +0.3V

 $V_{\rm HS}$ –0.3V to $V_{\rm HB}$ +0.3V

| Symbol | Parameter | Conditions | Min | Тур | Max | Units |
|-------------------|--|--|-----|------|------|-------|
| SUPPLY (| URRENTS | | | | | |
| I _{DD} | V _{DD} Quiescent Current | LI = HI = 0V | | 0.3 | 0.6 | mA |
| I _{DDO} | V _{DD} Operating Current | f = 500 kHz | | 1.8 | 2.9 | mA |
| I _{HB} | Total HB Quiescent Current | LI = HI = 0V | | 0.06 | 0.2 | mA |
| I _{HBO} | Total HB Operating Current | f = 500 kHz | | 1.4 | 2.8 | mA |
| I _{HBS} | HB to V _{SS} Current, Quiescent | $V_{HS} = V_{HB} = 90V$ | | 0.1 | 10 | μA |
| I _{HBSO} | HB to V _{SS} Current, Operating | f = 500 kHz | | 0.5 | | mA |
| | IS LI and HI | | | | | |
| V _{IL} | Low Level Input Voltage Threshold | | 0.8 | 1.8 | | V |
| V _{IH} | High Level Input Voltage Threshold | | | 1.8 | 2.2 | V |
| R _I | Input Pulldown Resistance | | 100 | 200 | 500 | kΩ |
| UNDER V | OLTAGE PROTECTION | 1 | | | | |
| V _{DDR} | V _{DD} Rising Threshold | $V_{DDR} = V_{DD} - V_{SS}$ | 6.0 | 6.7 | 7.4 | V |
| V _{DDH} | V _{DD} Threshold Hysteresis | | | 0.5 | | V |
| V _{HBR} | HB Rising Threshold | V _{HBR} = V _{HB} - V _{HS} | 5.7 | 6.6 | 7.1 | V |
| V _{HBH} | HB Threshold Hysteresis | | | 0.4 | | V |
| LO GATE | DRIVER | 1 | I | | | |
| V _{OLL} | Low-Level Output Voltage | I _{LO} = 100 mA | | 0.38 | 0.05 | |
| | | $V_{OHL} = V_{LO} - V_{SS}$ | | | 0.65 | V |
| V _{OHL} | High-Level Output Voltage | $I_{LO} = -100 \text{ mA},$ | | 0.72 | 1 00 | V |
| | | $V_{OHL} = V_{DD} - V_{LO}$ | | | 1.20 | V |
| I _{OHL} | Peak Pullup Current | $V_{LO} = 0V$ | | 1.0 | | А |
| I _{OLL} | Peak Pulldown Current | V _{LO} = 12V | | 1.0 | | А |
| HO GATE | DRIVER | | | | | |
| V _{OLH} | Low-Level Output Voltage | I _{HO} = 100 mA | | 0.38 | 0.65 | V |
| | | $V_{OLH} = V_{HO} - V_{HS}$ | | | 0.65 | |
| V _{OHH} | High-Level Output Voltage | $I_{HO} = -100 \text{ mA}$ | | 0.72 | 1.20 | V |
| | | $V_{OHH} = V_{HB} - V_{HO}$ | | 0.72 | 1.20 | |
| I _{онн} | Peak Pullup Current | $V_{HO} = 0V$ | | 1.0 | | А |
| I _{olh} | Peak Pulldown Current | V _{HO} = 12V | | 1.0 | | А |
| THERMAL | RESISTANCE | | | | | |
| θ_{JA} | Junction to Ambient | SOIC-8 (Note 3), (Note 5) | | 160 | | °C/W |
| | | LLP-8 (Note 3), (Note 5) | | 40 | | |

Switching Characteristics 可以的话的知道。 perature range. Unless otherwise specified, V_{DD} = V_{HB} = 12V, V_{SS} = V_{HS} = 0V, No Load on LO or HO.

| Symbol | Parameter | Conditions | Min | Тур | Max | Units |
|-----------------------------------|--|--------------------------|-----|-----|-----|-------|
| LM5109A | | | - I | 1 | 1 | |
| t _{LPHL} | Lower Turn-Off Propagation Delay (LI Falling to LO Falling) | | | 30 | 56 | ns |
| t _{HPHL} | Upper Turn-Off Propagation Delay (HI Falling to HO Falling) | | | 30 | 56 | ns |
| t _{LPLH} | Lower Turn-On Propagation Delay (LI Rising to LO Rising) | | | 32 | 56 | ns |
| t _{HPLH} | Upper Turn-On Propagation Delay (HI Rising to HO Rising) | | | 32 | 56 | ns |
| t _{MON} | Delay Matching: Lower Turn-On and Upper Turn-Off | | | 2 | 15 | ns |
| t _{MOFF} | Delay Matching: Lower Turn-Off and Upper Turn-On | | | 2 | 15 | ns |
| t _{RC} , t _{FC} | Either Output Rise/Fall Time | C _L = 1000 pF | | 15 | - | ns |
| t _{PW} | Minimum Input Pulse Width that Changes the Output | | | 50 | | ns |

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the component may occur. Operating Ratings are conditions under which operation of the device is guaranteed. Operating Ratings do not imply guaranteed performance limits. For guaranteed performance limits and associated test conditions, see the Electrical Characteristics tables.

Note 2: The human body model is a 100 pF capacitor discharged through a $1.5k\Omega$ resistor into each pin.

Note 3: 4 layer board with Cu finished thickness 1.5/1/1/1.5 oz. Maximum die size used. 5x body length of Cu trace on PCB top. 50 x 50mm ground and power planes embedded in PCB. See Application Note AN-1187.

Note 4: Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate National's Average Outgoing Quality Level (AOQL).

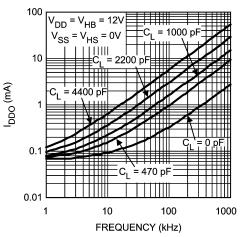
Note 5: The θ_{JA} is not a constant for the package and depends on the printed circuit board design and the operating conditions.

Note 6: In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently.

If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.

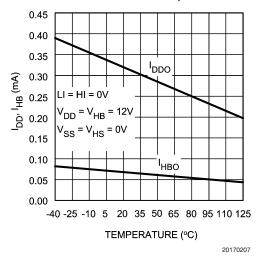
Typical Performance Characteristics 查询"LM5109A"供应商 Ver Operating Confent vs Frequency 100 $V_{DD} = V_{HB} = 12V$ $V_{SS} = V_{HS} = 0V$ = 1000 p 10 I_{DDO} (mA) 400 pl 1 470 pF 0.1 1 100 1000 10 FREQUENCY (kHz) 20170204 **Operating Current vs Temperature** 2.2 2.0 DDO C_L = 0 pF I_{DDO}, I_{HBO} (mA) 1.8 – = 500 kHz V_{DD} = V_{HB} = 12V 1.6 V_{SS} = V_{HS} = 0V 1.4 нво 1.2 1.0 -40 -25 -10 5 20 35 50 65 80 95 110 125 TEMPERATURE (°C) 20170206 **Quiescent Current vs Voltage** 600 LI = HI = 0V $500 \mid V_{DD} = V_{HB}$ $V_{SS} = V_{HS} = 0V$ DD 400 CURRENT (µA) 300 200 I_{HB} 100 0 10 8 12 14 16 18 $V_{DD}^{}, V_{HB}^{}(V)$ 20170208

HB Operating Current vs Frequency

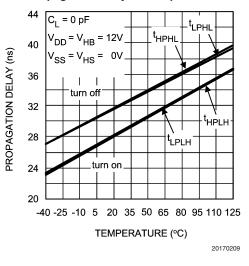


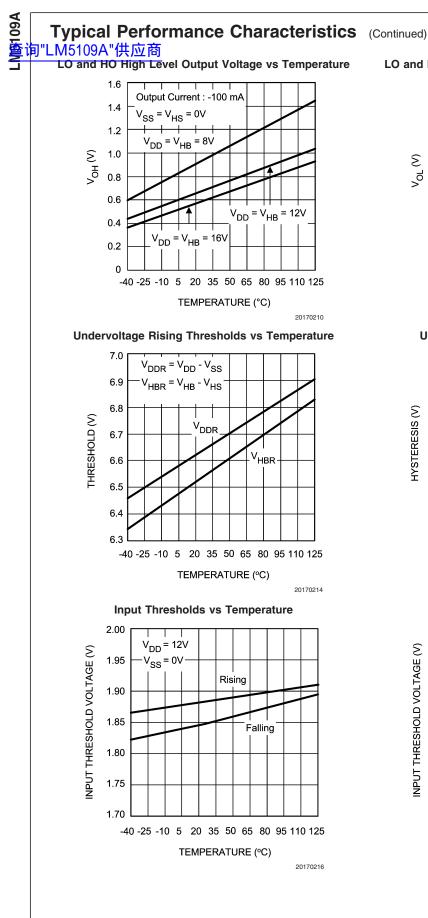
20170205

Quiescent Current vs Temperature

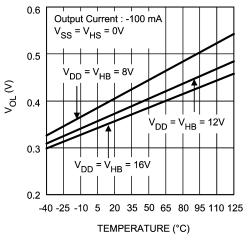


Propagation Delay vs Temperature



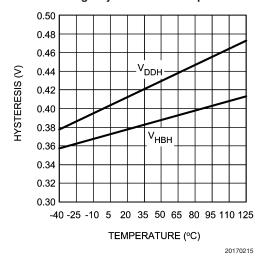


LO and HO Low Level Output Voltage vs Temperature

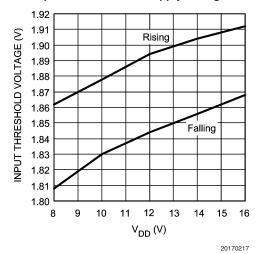




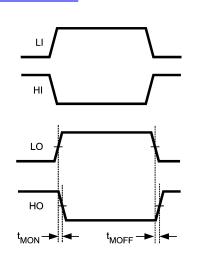
Undervoltage Hysteresis vs Temperature



Input Thresholds vs Supply Voltage



Timing Diagram 查询"LM5109A"供应商



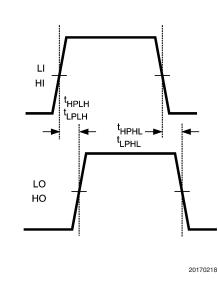


FIGURE 3.

Layout Considerations

Optimum performance of high and low-side gate drivers cannot be achieved without taking due considerations during circuit board layout. The following points are emphasized:

- Low ESR / ESL capacitors must be connected close to the IC between VDD and VSS pins and between HB and HS pins to support high peak currents being drawn from VDD and HB during the turn-on of the external MOS-FETs.
- 2. To prevent large voltage transients at the drain of the top MOSFET, a low ESR electrolytic capacitor and a good quality ceramic capacitor must be connected between the MOSFET drain and ground (VSS).
- In order to avoid large negative transients on the switch node (HS) pin, the parasitic inductances between the source of the top MOSFET and the drain of the bottom MOSFET (synchronous rectifier) must be minimized.
- 4. Grounding considerations:

a) The first priority in designing grounding connections is to confine the high peak currents that charge and discharge the MOSFET gates to a minimal physical area. This will decrease the loop inductance and minimize noise issues on the gate terminals of the MOSFETs. The gate driver should be placed as close as possible to the MOSFETs.

b) The second consideration is the high current path that includes the bootstrap capacitor, the bootstrap diode, the local ground referenced bypass capacitor, and the low-side MOSFET body diode. The bootstrap capacitor is recharged on a cycle-by-cycle basis through the bootstrap diode from the ground referenced VDD bypass capacitor. The recharging occurs in a short time interval and involves high peak current. Minimizing this loop length and area on the circuit board is important to ensure reliable operation.

HS Transient Voltages Below Ground

The HS node will always be clamped by the body diode of the lower external FET. In some situations, board resistances and inductances can cause the HS node to transiently swing several volts below ground. The HS node can swing below ground provided:

- HS must always be at a lower potential than HO. Pulling HO more than -0.3V below HS can activate parasitic transistors resulting in excessive current flow from the HB supply, possibly resulting in damage to the IC. The same relationship is true with LO and VSS. If necessary, a Schottky diode can be placed externally between HO and HS or LO and GND to protect the IC from this type of transient. The diode must be placed as close to the IC pins as possible in order to be effective.
- 2. HB to HS operating voltage should be 15V or less. Hence, if the HS pin transient voltage is -5V, VDD should be ideally limited to 10V to keep HB to HS below 15V.
- 3. Low ESR bypass capacitors from HB to HS and from VDD to VSS are essential for proper operation. The capacitor should be located at the leads of the IC to minimize series inductance. The peak currents from LO and HO can be quite large. Any series inductances with the bypass capacitor will cause voltage ringing at the leads of the IC which must be avoided for reliable operation.

